



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

1 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
Permanent Testing				
1	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-1
2	ELECTRONICS- EMC TEST FACILITY	Electrical / Electrical Product	Conducted Emission Test	IEC 60571
3	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Equipment System / Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS116-MIL-STD-461G
4	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Equipment System / Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS118-MIL-STD-461G
5	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Equipment System Subsystem	Conducted Susceptibility Bulk Cable Injection impulse Excitation	CS115-MIL-STD-461G
6	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Emission Test	BS EN 50121-4:2016+A1
7	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Emission Test	IEC 60945
8	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Emission Test	IEC 62236-3-2
9	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted RF Susceptibility Test	BS EN 50121-3-2:2016+A1
10	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted RF Susceptibility Test	BS EN 50121-4:2016+A1
11	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted RF Susceptibility Test	IEC 60571
12	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted RF Susceptibility Test	IEC 62236
13	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted RF Susceptibility Test	IEC 62236-3-2
14	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Susceptibility Bulk Cable Injection	CS114-MIL-STD-461G
15	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Susceptibility Power leads	CS 101-MIL-STD-461G
16	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Conducted Susceptibility Structure Current	CS 109-MIL-STD-461G
17	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrical Fast Transient (EFT) / Burst Immunity Test	BS EN 50121-3-2:2016+A1
18	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrical Fast Transient (EFT) / Burst Immunity Test	BS EN 50121-4:2016+A1



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR
7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

2 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
19	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrical Fast Transient (EFT) / Burst Immunity Test	IEC 60571
20	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrical Fast Transient (EFT) / Burst Immunity Test	IEC 62236-3-2
21	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrostatic Discharge Immunity Test	BS EN 50121-3-2:2016+A1
22	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrostatic Discharge Immunity Test	BS EN 50121-4:2016+A1
23	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrostatic Discharge Immunity Test	IEC 60571
24	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrostatic Discharge Immunity Test	IEC 62236-3-2
25	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Electrostatic Discharge Immunity Test	IEC 62236-3-2
26	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Power Frequency Magnetic Field Immunity Test	BS EN 50121-4:2016+A1
27	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Radiated Emission Test	BS EN 50121-3-2:2016+A1
28	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Radiated Emission Test	BS EN 50121-4:2016+A1
29	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Radiated Emission Test	IEC 60571
30	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Radiated Emission Test	IEC 62236-3-2
31	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Ring Wave Immunity Test	BS EN 61000-6-1
32	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Ring Wave Immunity Test	BS EN 61000-6-2
33	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Ring Wave Immunity Test	IEC 61000-6-1
34	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Ring Wave Immunity Test	IEC 61000-6-2
35	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Voltage Fluctuation & Flicker Test	IEC 60601-1-2:2014+A1
36	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 61000-6-3
37	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronic Product	Voltage Fluctuation & Flicker Test	IEC 61000-6-3
38	ELECTRONICS- EMC TEST FACILITY	Electrical / Electronics Product	Conducted Emission Test	IEC62236-3-2



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

3 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
39	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	BS EN 50121-3-2:2016+A1
40	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE101-MIL-STD-461F
41	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic equipment system/Subsystem	Conducted Emission	CE102-MIL-STD-461E
42	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	CE102-MIL-STD-461F
43	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	CE102-MIL-STD-461G
44	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission	CE101-MIL-STD-461E
45	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Emission Test	CE101-MIL-STD-461G
46	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk Cable Injection	CS 114-MIL-STD-461 E
47	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk cable Injection Impulse Excitation	CS 115 -MIL-STD-461 F
48	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk cable Injection Impulse Excitation	CS 115-MIL-STD-461 E
49	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Bulk Cable Injection	CS 114-MIL-STD-461 F
50	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS 116 MIL-STD-461 E
51	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Damped Sinusoidal Transients, Cable and Power Lead	CS 116-MIL-STD-461 F
52	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Power Leads	CS101-MIL-STD-461 E
53	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Power Leads	CS101-MIL-STD-461 F
54	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Structure Current	CS 109-MIL-STD-461 E
55	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Equipment System/Subsystem	Conducted Susceptibility Structure Current	CS 109-MIL-STD-461 F
56	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 24:2010+A1



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

4 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
57	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55024
58	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-1
59	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-6-2
60	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-1
61	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55011
62	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55014-1
63	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55015:2019+A11
64	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-3
65	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-3
66	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61326-1
67	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruption & Voltage Variations Immunity Test	BS EN 61000-4-29
68	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-4-2
69	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-2
70	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61326-1
71	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55014-2
72	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 55024
73	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 14-2:2015+A1
74	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 24:2010+A1



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard ISO/IEC 17025:2017

Certificate Number TC-6969

Validity 20/02/2025 to 19/02/2029

Page No 5 of 11

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
75	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	CISPR 35
76	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 60601-1-2:2014+A1
77	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-6-1
78	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-4-5
79	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-2
80	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55024
81	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 55014-2
82	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 60601-1-2:2015+A1
83	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-4-8
84	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-1
85	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	BS EN 61000-6-2
86	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 24:2010+A1
87	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	CISPR 35
88	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 60601-1-2:2014+A1
89	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-6-1
90	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61326-1
91	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 32:2015+A1
92	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55011
93	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55014-1
94	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 55022



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard ISO/IEC 17025:2017

Certificate Number TC-6969

Validity 20/02/2025 to 19/02/2029

Page No 6 of 11

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
95	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 60601-1-2:2015+A1
96	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-3
97	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	BS EN 61000-6-4
98	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 14-1
99	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	CISPR 22
100	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 60601-1-2:2014+A1
101	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-3
102	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61000-6-4
103	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	IEC 61326-1
104	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-2
105	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 24:2010+A1
106	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 60601-1-2:2014+A1
107	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55014-2
108	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 55024
109	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 60601-1-2:2015+A1
110	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-4-3
111	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	BS EN 61000-6-1
112	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 14-2:2015+A1
113	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	CISPR 35
114	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-6-2



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR
7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

7 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
115	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61326-1
116	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 55014-2
117	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-4-11
118	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 14-2:2015+A1
119	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61326-1
120	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 60601-1-2:2015+A1
121	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	CISPR 35
122	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 60601-1-2:2015+A1
123	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	BS EN 61000-3-3:2013+A2
124	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 55022
125	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 60601-1-2:2015+A1
126	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	BS EN 61000-6-4
127	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 11
128	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 14-1
129	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	CISPR 22
130	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	FCC Part 15B & 18
131	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 60601-1-2:2014+A1
132	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted Emission	IEC 61000-6-4

This is annexure to 'Certificate of Accreditation' and does not require any signature.



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

8 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
133	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55014-2
134	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 55024
135	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 60601-1-2:2015+A1
136	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-4-6
137	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-1
138	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	BS EN 61000-6-2
139	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 14-2:2015+A1
140	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 24:2010+A1
141	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	CISPR 35
142	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 60601-1-2:2014+A1
143	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-4-6
144	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-1
145	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Conducted RF Susceptibility Test	IEC 61000-6-2
146	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	DC Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-29
147	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55014-2
148	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 55024
149	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 60601-1-2:2015+A1
150	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-4-4
151	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-1
152	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	BS EN 61000-6-2

This is annexure to 'Certificate of Accreditation' and does not require any signature.



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

9 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
153	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 24:2010+A1
154	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	CISPR 35
155	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 60601-1-2:2014+A1
156	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-4-4
157	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-1
158	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61000-6-2
159	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrical Fast Transient (EFT)/ Burst Immunity Test	IEC 61326-1
160	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 60601-1-2:2015+A1
161	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-1
162	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	BS EN 61000-6-2
163	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Electrostatic Discharge Immunity Test	IEC 61000-4-2
164	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55014-2
165	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 55024
166	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 60601-1-2:2015+A1
167	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-1
168	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	BS EN 61000-6-2
169	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 24:2010+A1
170	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR 35
171	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	CISPR14-2:2015+A1
172	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 60601-1-2:2014+A1



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name :

EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR
7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard

ISO/IEC 17025:2017

Certificate Number

TC-6969

Page No

10 of 11

Validity

20/02/2025 to 19/02/2029

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
173	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-1
174	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61000-6-2
175	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy / Telecom Surge Immunity Test	IEC 61326-1
176	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	High Energy/Telecom Surge Immunity Test	IEC 61000-4-5:2014+A1
177	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Power Frequency Magnetic Field Immunity Test	IEC 61000-4-8
178	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Test	FCC Part 15B & 18
179	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Radiated Emission Testing	CISPR 11
180	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	RF Radiated Susceptibility Test	IEC 61000-4-3
181	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	BS EN 61000-4-12
182	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Ring Wave Immunity Test	IEC 61000-4-12
183	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 61000-4-11
184	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	BS EN 61000-6-2
185	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic product	Voltage dips, Short Interruptions & Voltage Variations Immunity Test	IEC 60601-1-2:2014+A1
186	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Product	Voltage Fluctuation & Flicker Test	IEC 61000-3-3:2013+A1:2017+A2
187	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 15:2018+A1
188	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Conducted Emission	CISPR 32:2015+A1
189	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 60601-1-2:2015+A1
190	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-3-2:2019+A1
191	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	BS EN 61000-6-3



National Accreditation Board for Testing and Calibration Laboratories

SCOPE OF ACCREDITATION

Laboratory Name : EMC DIVISION, SAMEER - CENTRE FOR MICROWAVE RESEARCH, SECTOR 7, RAIN TREE MARG, NAVI MUMBAI, MAHARASHTRA, INDIA

Accreditation Standard ISO/IEC 17025:2017

Certificate Number TC-6969

Validity 20/02/2025 to 19/02/2029

Page No 11 of 11

Last Amended on 13/05/2025

S.No	Discipline / Group	Materials or Products tested	Component, parameter or characteristic tested / Specific Test Performed / Tests or type of tests performed	Test Method Specification against which tests are performed and / or the techniques / equipment used
192	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-6-3
193	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 60601-1-2:2014+A1
194	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronic Products	Harmonic Current Emission Test	IEC 61000-3-2:2018+A1:2020+A2
195	ELECTRONICS- EMC TEST FACILITY	Electrical/Electronics products	Conducted RF Susceptibility Test	IEC 61326-1